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Application Number 10/519349

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Applicant(s)

Hillenbrand, et al.

/ Customer Number 041068

Filing Date

Group Art Unit 2884

				27 December 2004	(371 date)	-Not-Y	t-Assigned	-
		· · · · · · · · · · · · · · · · · · ·	U.S	. PATENT DOCUMENTS				
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING IF APPRO	
/CI/	AA	6408123	18 Jun 2002	Kuroda, et al.			9 Nov 2000	
/CI/	АВ	5602820	11 Feb 1997	Wickramasinghe, et al.			24 Aug 1995	
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/CI/	AD	DE 10035134 A1	14 Feb 2002	Germany			SUMMARY	
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